INTEGRATED CIRCUITS

DATA SHEET

74LVT323743.3 V 32-bit edge-triggered D-type flip-flop; 3-state

Product specification Supersedes data of 2002 Mar 20

2004 Oct 15





3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374

FEATURES

- 32-bit edge-triggered flip-flop
- · 3-state buffers
- Output capability: +64 mA/-32 mA
- TTL input and output switching levels
- Input and output interface capability to systems at 5 V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- · Live insertion/extraction permitted
- · Power-up reset
- · Power-up 3-state
- . No bus current loading when output is tied to 5 V bus
- Latch-up protection exceeds 500 mA in accordance with JEDEC std 17
- ESD protection exceeds 2000 V in accordance with MIL STD 883 method 3015 and 200 V in accordance with machine model.

DESCRIPTION

The 74LVT32374 is a high-performance BICMOS product designed for V_{CC} operation at 3.3 V.

The 74LVT32374 is a 32-bit edge-triggered D-type flip-flop featuring non-inverting 3-state outputs. The device can be used as four 8-bit flip-flops, or two 16-bit flip-flops or one 32-bit flip-flop. On the positive transition of the clock (CP), the Q outputs of the flip-flop take on the logic levels set-up at the D inputs.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25 \, ^{\circ}C$; $t_r = t_f \le 2.5 \, \text{ns}$.

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t _{PHL} /t _{PLH}	propagation delay nCP to nQ _n	$C_L = 50 \text{ pF}; V_{CC} = 3.3 \text{ V}$	2.9	ns
C _I	input capacitance	V _I = 0 V or 3.0 V	3	pF
Co	output capacitance	outputs disabled; $V_0 = 0 \text{ V or } 3.0 \text{ V}$	9	pF
I _{CCZ}	total supply current	output disabled; V _{CC} = 3.6 V	140	μΑ

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374

FUNCTION TABLE

See note 1.

OPERATING MODE		INPUT		INTERNAL	
OPERATING MODE	nOE	nCP	nD _n	REGISTER	nQ _n
Load and read register	L	1	I	L	L
	L	1	h	Н	Н
Hold	L	1	Х	NC	NC
Disable outputs	Н	1	Х	NC	Z
	Н	1	nD _n	nD _n	Z

Note

1. H = HIGH voltage level;

h = HIGH voltage level one set-up time prior to the HIGH-to-LOW OE transition;

L = LOW voltage level;

I = LOW voltage level one set-up time prior to the HIGH-to-LOW OE transition;

NC = not connected;

X = don't care;

Z = high-impedance OFF-state;

↑ = LOW-to-HIGH CP transition;

♦ = not a LOW-to-HIGH CP transition.

ORDERING INFORMATION

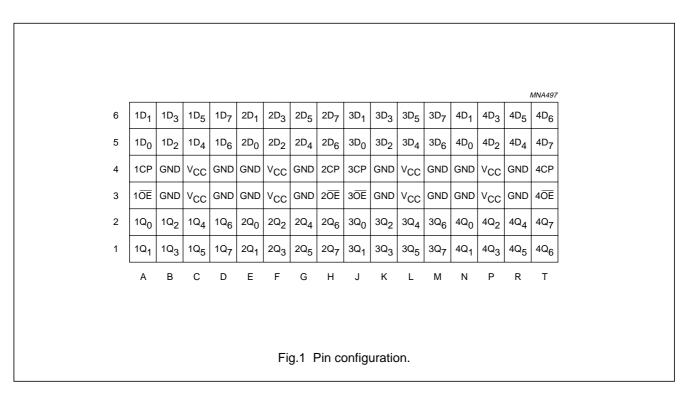
TYPE NUMBER	TEMPERATURE		PAC	(AGE	
TIPE NOWBER	RANGE	PINS	PACKAGE	MATERIAL	CODE
74LVT32374EC	-40 °C to +85 °C	96	LFBGA96	plastic	SOT536-1

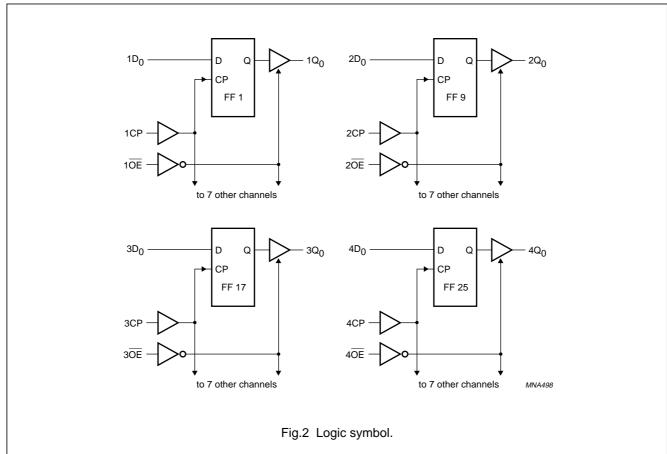
PINNING

SYMBOL	DESCRIPTION	
nD _n	data input	
nCP	clock input	
nQ _n	flip-flop output	
GND	ground (0 V)	
nOE	output enable input (active LOW)	
V _{CC}	supply voltage	

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

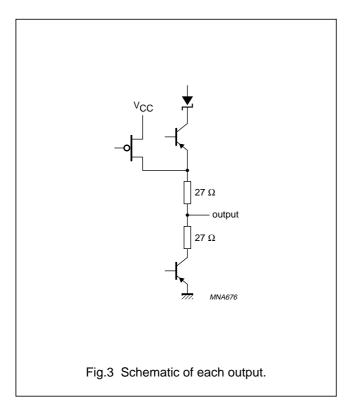
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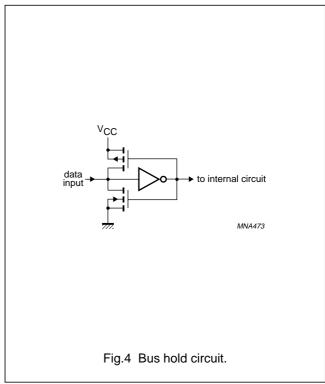




3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374





RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{CC}	supply voltage		2.7	+3.6	V
VI	input voltage	note 1	0	5.5	V
V _{IH}	HIGH-level input voltage		2.0	_	V
V _{IL}	LOW-level input voltage		_	0.8	V
I _{OH}	HIGH-level output current		_	-32	mA
I _{OL}	LOW-level output current		_	32	mA
		current duty cycle ≤ 50 %; f ≥ 1 kHz	_	64	mA
Δt/ΔV	input transition rise or fall times	outputs enabled	_	10	ns/V
T _{amb}	ambient temperature		-40	+85	°C
P _{tot}	power dissipation per package	note 2	_	1000	mW

Notes

- 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
- 2. Above 70 $^{\circ}\text{C}$ the value of P_{tot} derates linearly with 1.8 mW/K.

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); note 1.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{CC}	supply voltage		-0.5	_	+4.6	V
I _{IK}	input diode current	V _I < 0 V	_	-50	_	mA
VI	input voltage	note 2	-0.5	_	+7.0	V
I _{OK}	output diode current		_	-50	_	mA
Vo	output voltage	output in OFF or HIGH state; note 2	-0.5	_	+7.0	V
Io	output current	output in LOW state	_	128	_	mA
		output in HIGH state	_	-64	_	mA
T _{stg}	storage temperature		-65	_	+150	°C

Notes

- 1. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.
- 2. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374

DC CHARACTERISTICS

Over recommended operating conditions; voltages are referenced to GND (ground = 0 V).

CAMBOI	DADAMETED	TEST CONDITIONS	3	MINI	TVD (1)	-VD (1) B4 A V	
SYMBOL	PARAMETER OTHER		V _{CC} (V)	MIN.	TYP. ⁽¹⁾	MAX.	UNIT
T _{amb} = -40) °C to +85 °C		•		·		
V _{IK}	input clamp voltage	I _{IK} = −18 mA	2.7	_	-0.85	-1.2	V
V _{OH}	HIGH-level output voltage	I _{OH} = -32 mA	3.0	2.0	2.3	_	V
V _{OL}	LOW-level output voltage	I _{OL} = 64 mA	3.0	_	0.4	0.55	V
V _{RST}	power-up output LOW voltage	$I_O = -1$ mA; $V_I = GND$ or V_{CC} ; note 2	3.6	_	0.1	0.55	V
ILI	input leakage current	$V_I = V_{CC}$ or GND; control pins	3.6	_	0.1	±1	μΑ
		V _I = 5.5 V	0 or 3.6	_	0.4	10	μΑ
		V _I = V _{CC} ; data pins; note 3	3.6	_	0.1	1	μΑ
		V _I = 0 V; data pins; note 3	3.6	_	-0.4	-5	μΑ
l _{off}	output OFF current	V_I or $V_O = 0$ V to 4.5 V	0	_	0.1	±100	μΑ
I _{hold}	bus hold current D inputs	V _I = 0.8 V; note 4	3.0	75	135	_	μΑ
		V _I = 2.0 V; note 4	3.0	-75	-135	_	μΑ
		V _{CC} = 3.6 V; note 4	0 to 3.6	±500	_	_	μΑ
I _{EX}	current into an output in the HIGH state when V _O > V _{CC}	V _O = 5.5 V	3.0	-	50	125	μΑ
I _{pu/pd}	power-up/down 3-state output current	$V_O = 5.5 \text{ V to V}_{CC};$ $V_I = \text{GND or V}_{CC};$ $V_{OE} = \text{don't}$ care; note 5	≤ 1.2 V	_	1	±100	μА
I _{OZH}	3-state output HIGH current	$V_O = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}$	3.6	_	0.5	5	μΑ
I _{OZL}	3-state output LOW current	$V_O = 0.5 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}$	3.6	_	+0.5	-5	μΑ
I _{CCH}	quiescent supply current	outputs HIGH; $I_O = 0$ A; $V_I = GND$ or V_{CC}	3.6	_	0.14	0.24	mA
I _{CCL}	quiescent supply current	outputs LOW; I _O = 0 A; V _I = GND or V _{CC}	3.6	-	8	12	mA
I _{CCZ}	quiescent supply current	outputs disabled; $I_O = 0 A$; $V_I = GND \text{ or } V_{CC}$; note 6	3.6	-	0.14	0.24	mA
ΔI_{CC}	additional supply current per input pin	one input at V_{CC} – 0.6 V; other inputs at GND or V_{CC} ; note 7	3.0 to 3.6	-	0.1	0.2	μА

Notes

- 1. All typical values are measured at V_{CC} = 3.3 V and T_{amb} = 25 °C.
- 2. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.
- 3. Unused pins at V_{CC} or GND.
- 4. This is the bus hold overdrive current required to force the input to the opposite logic state.
- 5. This parameter is valid for any V_{CC} between 0 V and 1.2 V with a transition time of up to 10 ms. From V_{CC} = 1.2 V to V_{CC} = 3.3 V \pm 0.3 V a transition time of 100 μs is permitted. This parameter is valid for T_{amb} = 25 °C only.
- 6. I_{CCZ} is measured with outputs pulled to V_{CC} or GND.
- 7. This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND.

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374

AC CHARACTERISTICS

GND = 0 V; t_r = $t_f \leq$ 2.5 ns; C_L = 50 pF; R_L = 500 $\Omega.$

OVMDOL	DADAMETED	CONDITIO	ONDITIONS	24121	TVD (1)	MAN		
SYMBOL	PARAMETER	WAVEFORMS	V _{CC} (V)	MIN.	TYP. ⁽¹⁾	MAX.	UNIT	
T _{amb} = -40	°C to +85 °C	1		!	!	!		
t _{PLH} pr	propagation delay nCP to nQ _n	see Fig.5	2.7	_	_	6.2	ns	
			3.0 to 3.6	1.5	3.0	5.3	ns	
t _{PHL}	propagation delay	see Fig.5	2.7	_	_	5.1	ns	
	nCP to nQ _n		3.0 to 3.6	1.5	3.0	4.9	ns	
t _{PZH}	output enable time to	see Figs 7 and 8	2.7	_	_	6.9	ns	
	HIGH level		3.0 to 3.6	1.5	3.5	5.6	ns	
t _{PZL}	output enable time to	see Figs 7 and 8	2.7	_	_	6.0	ns	
	LOW level		3.0 to 3.6	1.5	3.2	4.9	ns	
t _{PHZ}	output disable time from	see Figs 7 and 8	2.7	_	_	5.7	ns	
	HIGH level		3.0 to 3.6	1.5	3.5	5.4	ns	
t _{PLZ}	output disable time from LOW level	see Figs 7 and 8	2.7	1.5	3.2	5.1	ns	
			3.0 to 3.6	1.5	3.2	5.0	ns	
suH	set-up time	see Fig.6	2.7	2.0	_	_	ns	
	nD _n HIGH to nCP		3.0 to 3.6	2.0	0.7	_	ns	
t _{suL}	set-up time	see Fig.6	2.7	2.0	_	-	ns	
	nD _n LOW to nCP		3.0 to 3.6	2.0	0.7	_	ns	
t _{hH}	hold time	see Fig.6	2.7	0.1	_	_	ns	
	nD _n HIGH to nCP		3.0 to 3.6	0.8	0	-	ns	
t _{hL}	hold time	see Fig.6	2.7	0.1	_	_	ns	
	nD _n LOW to nCP		3.0 to 3.6	0.8	0	_	ns	
t _{WH}	nCP HIGH pulse width	see Fig.6	2.7	1.5	_	_	ns	
			3.0 to 3.6	1.5	0.6	_	ns	
t _{WL}	nCP LOW pulse width	see Fig.6	2.7	3.0	_	_	ns	
			3.0 to 3.6	3.0	1.6	_	ns	
f _{max}	maximum clock pulse frequency	see Fig.5	3.0 to 3.6	150	_	_	MHz	

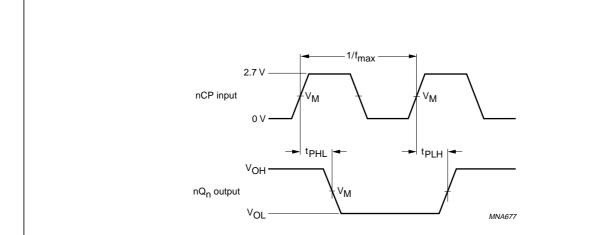
Note

1. All typical values are measured at V_{CC} = 3.3 V and T_{amb} = 25 °C.

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

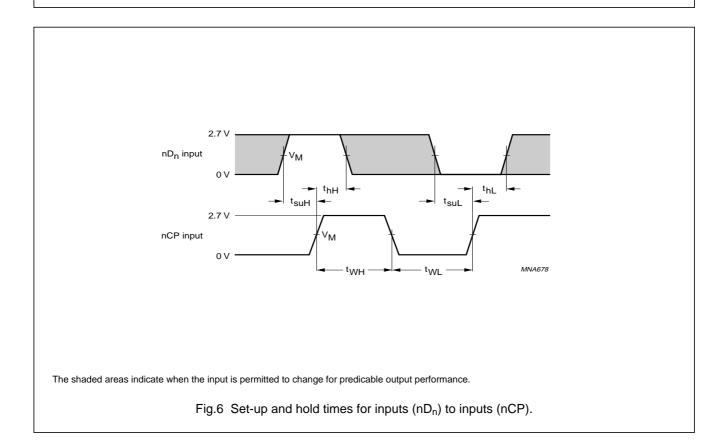
74LVT32374

AC WAVEFORMS



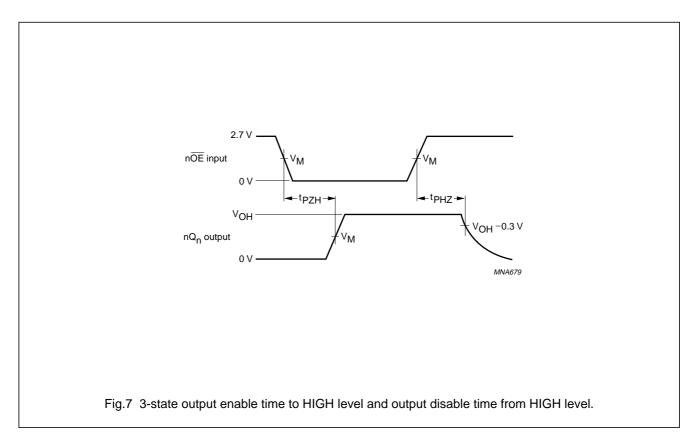
 $V_M = 1.5 \text{ V};$ $V_M = \text{GND to } 3.0 \text{ V}.$

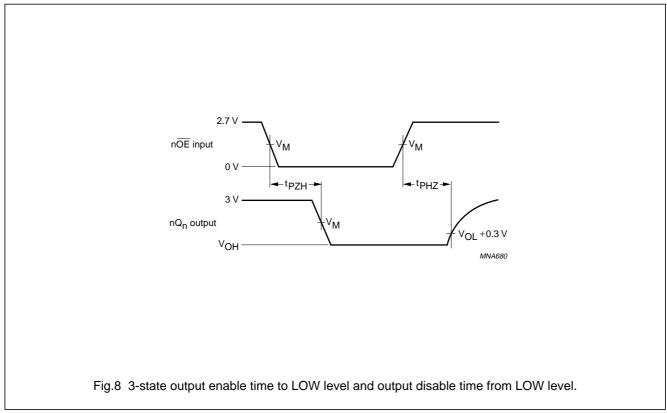
Fig.5 Clock (nCP) to output (nQ_n) propagation delays, the clock pulse width and the maximum clock pulse frequency.



3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

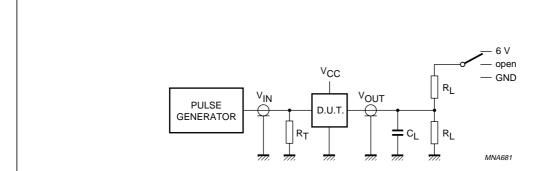
74LVT32374





3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374



TEST	SWITCH
t _{PLH} /t _{PHL}	open
t _{PLZ} /t _{PZL}	6 V
t _{PHZ} /t _{PZH}	GND

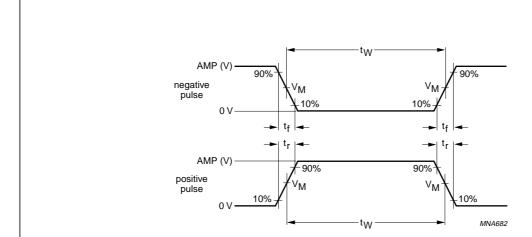
Definitions for test circuit:

R_L = Load resistor.

C_L = Load capacitance including jig and probe capacitance.

 R_T = Termination resistance should be equal to the output impedance Z_0 of the pulse generator.

Fig.9 Load circuitry for switching times.



INPUT PULSE REQUIREMENTS				
AMPLITUDE	PULSE RATE	t _W	t _r	t _f
2.7 V	≤ 10 MHz	500 ns	≤ 2.5 ns	≤ 2.5 ns

Fig.10 Input pulse definition.

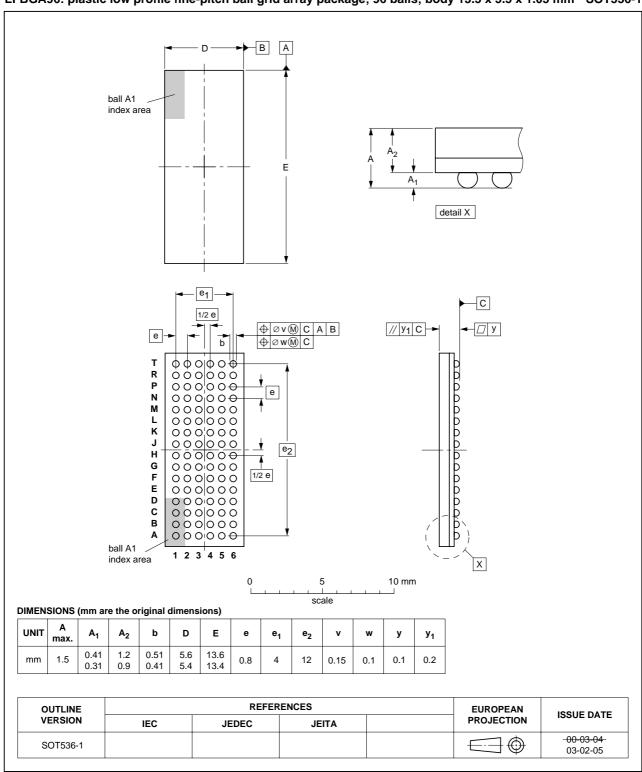
2004 Oct 15

3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

74LVT32374

PACKAGE OUTLINE

LFBGA96: plastic low profile fine-pitch ball grid array package; 96 balls; body 13.5 x 5.5 x 1.05 mm SOT536-1



3.3 V 32-bit edge-triggered D-type flip-flop;3-state

74LVT32374

DATA SHEET STATUS

LEVEL	DATA SHEET STATUS ⁽¹⁾	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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2004 Oct 15

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